

Notice of References Cited	Application/Control No. 10/017,021	Applicant(s)/Patent Under Reexamination YUTKOWITZ, STEPHEN J.	
	Examiner Joshua C Liu	Art Unit 2121	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-4,623,971	11-1986	Ailman et al.	700/252
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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